



INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. KUB-006		U.S. APPLICATION NO. 10/594,842	
				APPLICANT Masahiro MURAKAWA et al.			
				FILING DATE September 28, 2006		GROUP 3715	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE	
FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	EP 1 645 995 A1	04/12/2006	Europe			X	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	XP007907517; "Chapter 3: Genetic Algorithm for Deep-Submicron MOSFET Simulation" A GENETIC ALGORITHM FOR DEEP-SUBMICRON MOSFET PARAMETERS EXTRACTION AND SIMULATION, July 1, 2002; page 19-29						
	XP007907548; "Chapter 4: Simulation Results and Discussion" A GENETIC ALGORITHM FOR DEEP-SUBMICRON MOSFET PARAMETERS EXTRACTION AND SIMULATION, July 2002, pages 30-36						
	XP007907547; "Chapter 5: Conclusions"; A GENETIC ALGORITHM FOR DEEP-SUBMICRON MOSFET PARAMETERS EXTRACTION AND SIMULATION, July 2002, pages 37-38						
	XP007907512; "Application of the Genetic Algorithm to Compact MOSFET Model Development and Parameter Extraction"; X. Cai*, H. Wang*, X. Gu*&, G. Gildenblat* and P. Bendix**; TECHNICAL PROCEEDINGS OF THE 2003 NANOTECHNOLOGY CONFERENCE AND TRADE SHOW (NANOTECH'03), vol. 2, February 23, 2003 – February 27, 2003, pages 314-317						
	XP007907555; "Automatic BSIM3/4 Model Parameter Extraction with Penalty Function"; Y. Mahotin and E. Lyumkis; TECHNICAL PROCEEDINGS OF THE 2004 NANOTECHNOLOGY CONFERENCE AND TRADE SHOW (NANOTECH'04), vol. 2, March 7, 2004 – March 11, 2004, pages 167-170						
	XP007907426; "Extraction of Compact Model Parameters for ULSI MOSFETs Using a Genetic Algorithm"; TECHNICAL PROCEEDINGS OF THE 1999 INTERNATIONAL CONFERENCE ON MODELLING AND SIMULATION OF MICROSYSTEMS (MSM'99); April 19, 1999 - April 21, 1999, pages 176-179						
	XP007907525; "Simplex Crossover and Linkage Identification: Single-Stage Evolution VS. Multi-Stage Evolution"; PROCEEDINGS OF THE 2002 CONGRESS ON EVOLUTIONARY COMPUTATION (CEC'02), vol. 1, May 12, 2002 – May 17, 2002, pages 974-979						
	XP007907577; "A Trial Report HiSIM-1.2 Parameter Extraction for 90 nm Technology"; TECHNICAL PROCEEDINGS OF THE 2004 NANOTECHNOLOGY CONFERENCE AND TRADE SHOW (NANOTECH'04), vol. 2, March 7, 2004 – March 11, 2004, pages 147-150						
	XP010814331; "Towards Automatic Parameter Extraction for Surface-Potential-Based MOSFET Models with the Genetic Algorithm"; PROCEEDINGS OF THE 2005 ASIA AND SOUTH PACIFIC DESIGN AUTOMATION CONFERENCE (ASP-DAC'05), vol. 1, January 18, 2005 – January 21, 2005, pages 204-207						
	XP007907539; "Genetic Algorithm for Reliable Parameter Extraction of Complete Surface-Potential-Based Models"; PROCEEDINGS OF THE 2 ND INTERNATIONAL WORKSHOP ON COMPACT MODELING (IWCM'05), January 20, 2005, pages 7-12						
EXAMINER				DATE CONSIDERED			

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.